

**Main Product Characteristics:**

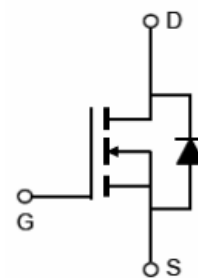
$V_{DSS}$	100V
$R_{DS(on)}$	10.5m $\Omega$ (typ.)
$I_D$	57A



TO-263



Marking and Pin Assignment



Schematic Diagram

**Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature


**Description:**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

**Absolute max Rating:**

Symbol	Parameter	Max.	Units
$I_D$ @ TC = 25°C	Continuous Drain Current, $V_{GS}$ @ 10V ①	57	A
$I_{DM}$	Pulsed Drain Current ②	190	
$P_D$ @TC = 25°C	Power Dissipation ③	170	W
$V_{DS}$	Drain-Source Voltage	100	V
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{AS}$	Single Pulse Avalanche Energy @ L=0.3mH	86.4	mJ
$I_{AS}$	Single Pulse Avalanche Current @ L=0.3mH	24	A
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	°C

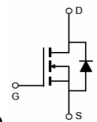
## Thermal Resistance

Symbol	Characterizes	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-case ③	—	0.88	$^{\circ}\text{C}/\text{W}$

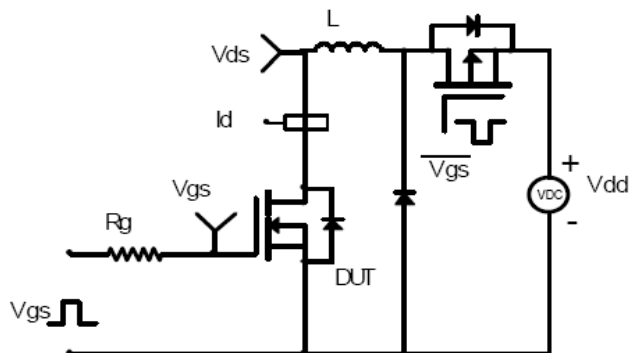
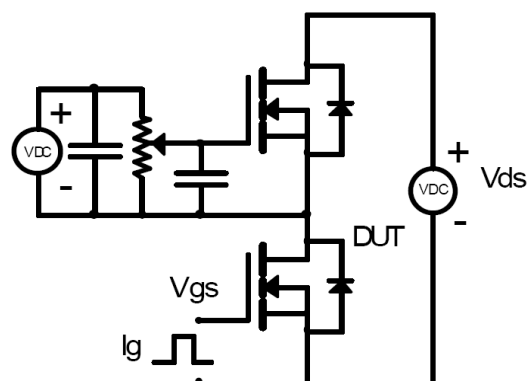
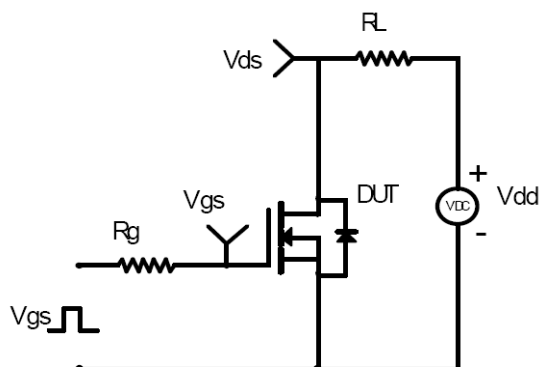
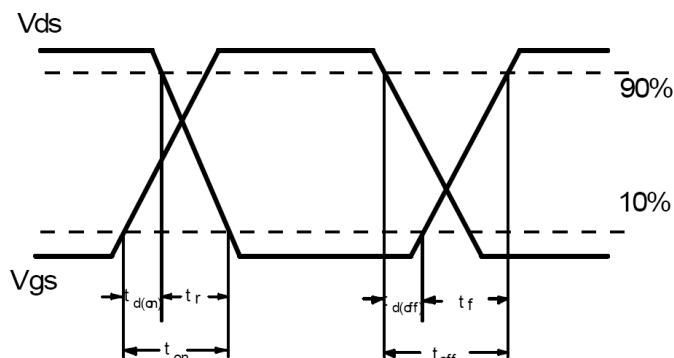
## Electrical Characterizes @ $T_A=25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	100	—	—	V	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	10.5	16	m $\Omega$	$V_{GS}=10\text{V}, I_D=30\text{A}$
$V_{GS(th)}$	Gate threshold voltage	2	—	4	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
$I_{DSS}$	Drain-to-Source leakage current	—	—	1	$\mu\text{A}$	$V_{DS} = 100\text{V}, V_{GS} = 0\text{V}$
$I_{GSS}$	Gate-to-Source forward leakage	—	—	100	nA	$V_{GS} = 20\text{V}$
		—	—	-100		$V_{GS} = -20\text{V}$
$Q_g$	Total gate charge	—	94	—	nC	$I_D = 28\text{A},$ $V_{DS}=80\text{V},$ $V_{GS} = 10\text{V}$
$Q_{gs}$	Gate-to-Source charge	—	15	—		
$Q_{gd}$	Gate-to-Drain("Miller") charge	—	22	—		
$t_{d(on)}$	Turn-on delay time	—	17.3	—	ns	$V_{GS}=10\text{V}, V_{DS}=40\text{V},$ $R_{GEN}=2.2\Omega$ $I_D = 18\text{A}$
$t_r$	Rise time	—	29.1	—		
$t_{d(off)}$	Turn-Off delay time	—	46.3	—		
$t_f$	Fall time	—	9.1	—		
$C_{iss}$	Input capacitance	—	3488	—	pF	$V_{GS} = 0\text{V}$ $V_{DS} = 100\text{V}$ $f = 1\text{MHz}$
$C_{oss}$	Output capacitance	—	191	—		
$C_{rss}$	Reverse transfer capacitance	—	144	—		

## Source-Drain Ratings and Characteristics

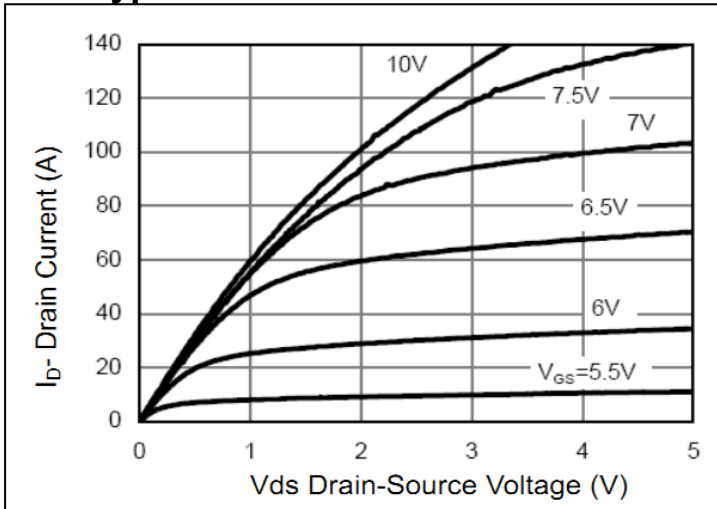
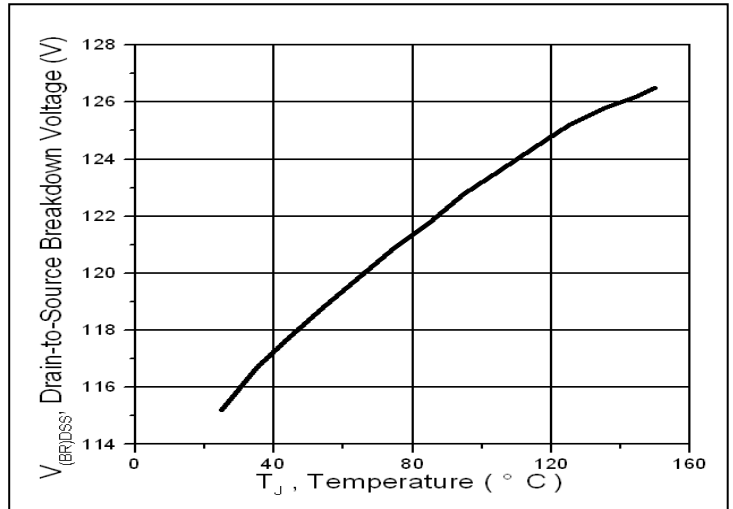
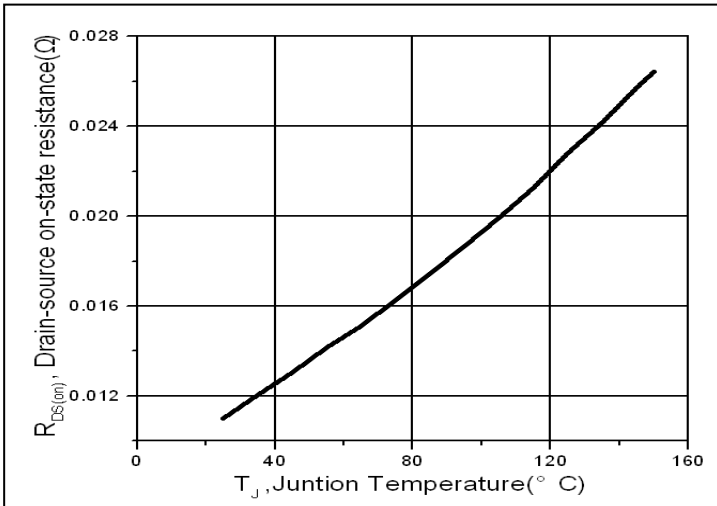
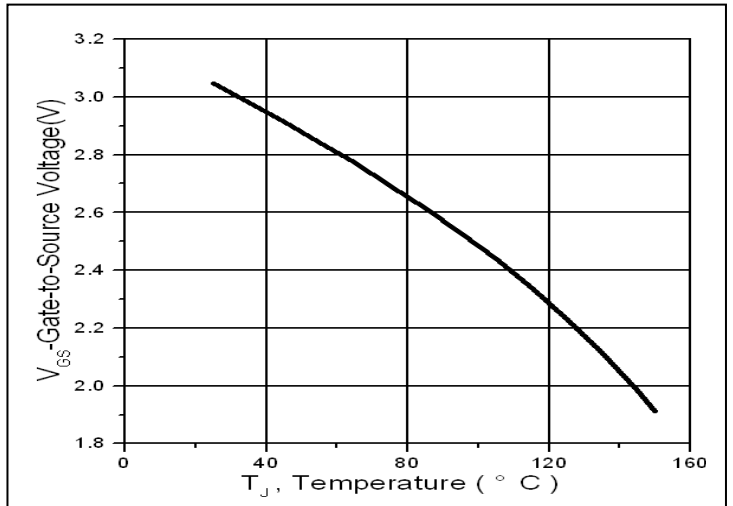
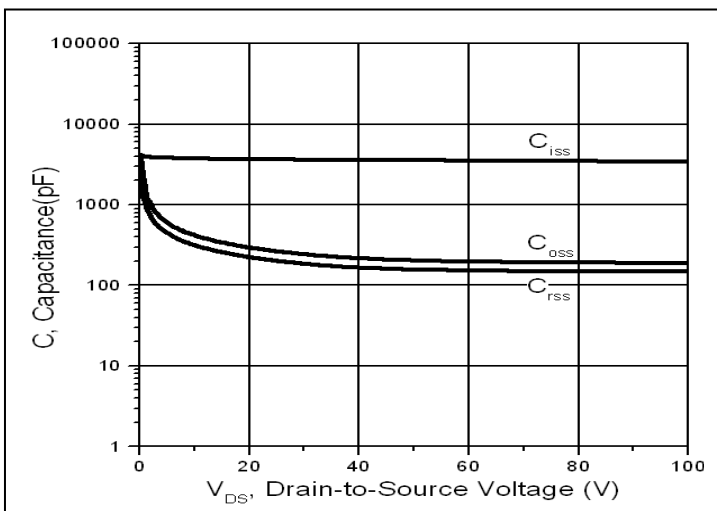
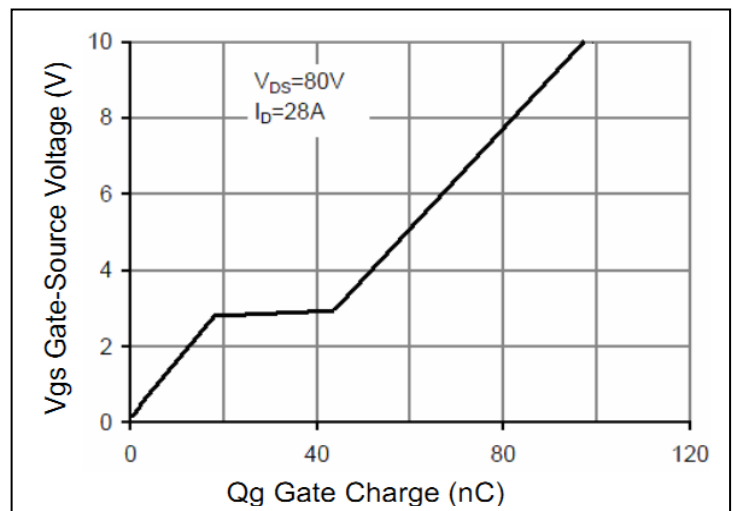
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	57	A	MOSFET symbol showing the integral reverse p-n junction diode. 
$V_{SD}$	Diode Forward Voltage	—	—	1.2	V	$I_S=28\text{A}, V_{GS}=0\text{V}$
$t_{rr}$	Reverse Recovery Time	—	35	—	ns	$I_S=28\text{A}, di/dt=100\text{A}/\mu\text{s}$
$Q_{rr}$	Reverse Recovery Charge	—	55	—	nC	

## Test circuits and Waveforms

**EAS Test Circuit:**

**Gate charge test circuit:**

**Switching Time Test Circuit:**

**Switching Waveforms:**


### Notes:

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.

**Typical electrical and thermal characteristics**

**Figure 1: Typical Output Characteristics**

**Figure 2: Drain-to-Source Breakdown Voltage vs. Temperature**

**Figure 3: Normalized On-Resistance Vs. Case Temperature**

**Figure 4: Gate to source cut-off voltage**

**Figure 5: Capacitance vs Vds**

**Figure 6: Gate Charge**

Typical electrical and thermal characteristics

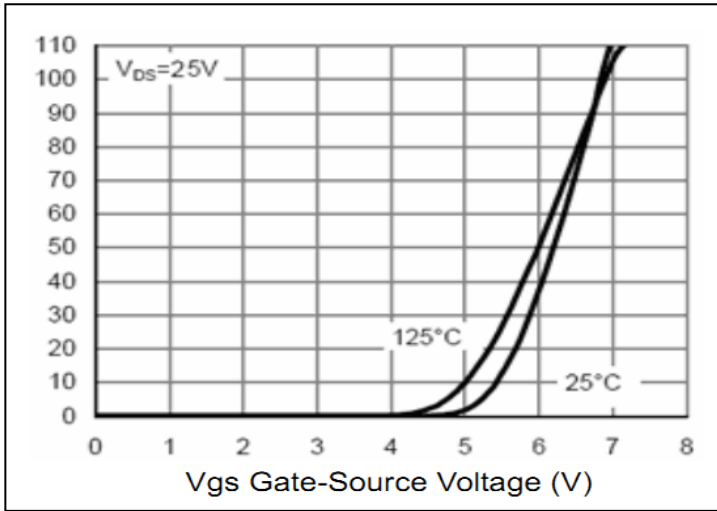


Figure 7: Transfer Characteristics

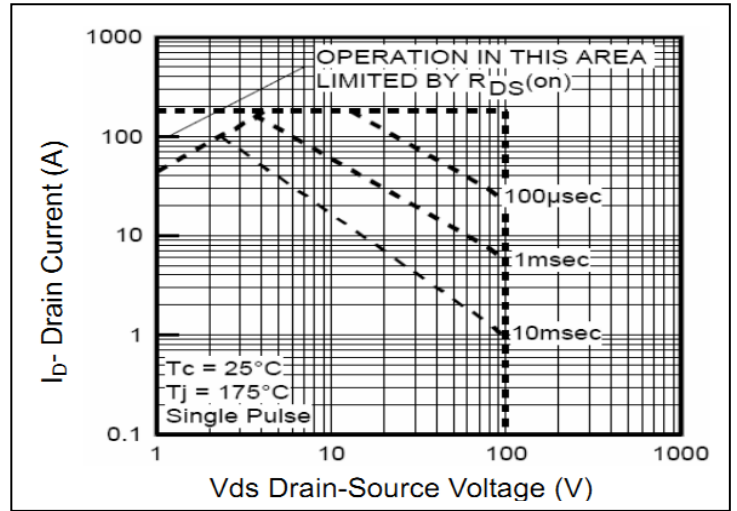


Figure 8: Safe Operation Area

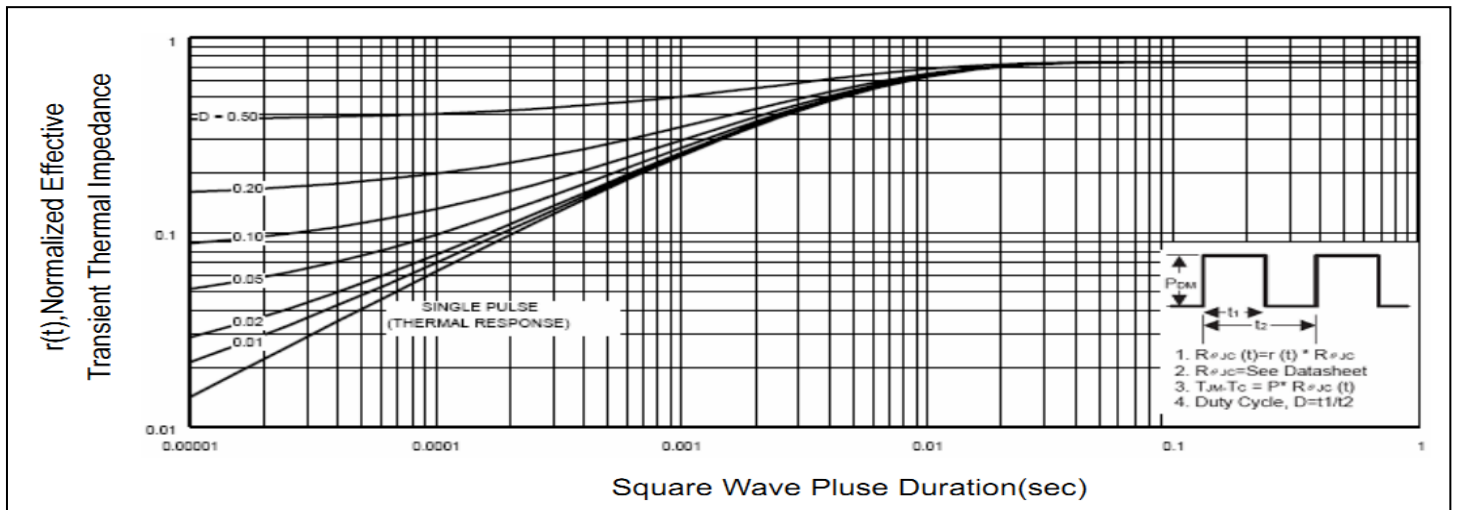


Figure 9: Normalized Maximum Transient Thermal Impedance

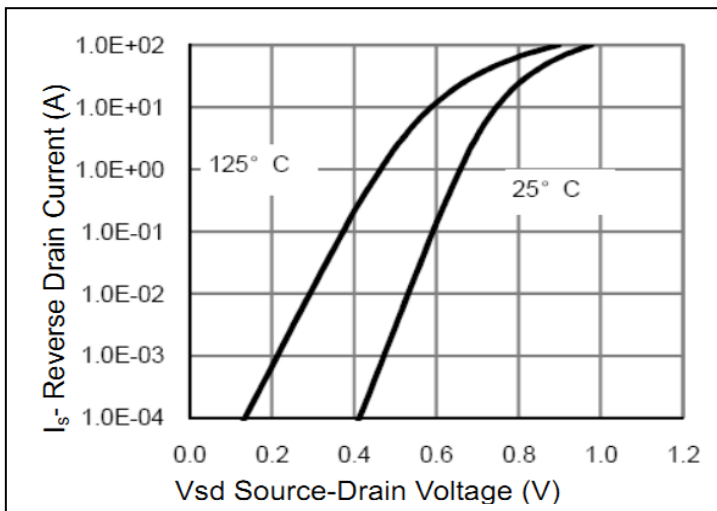
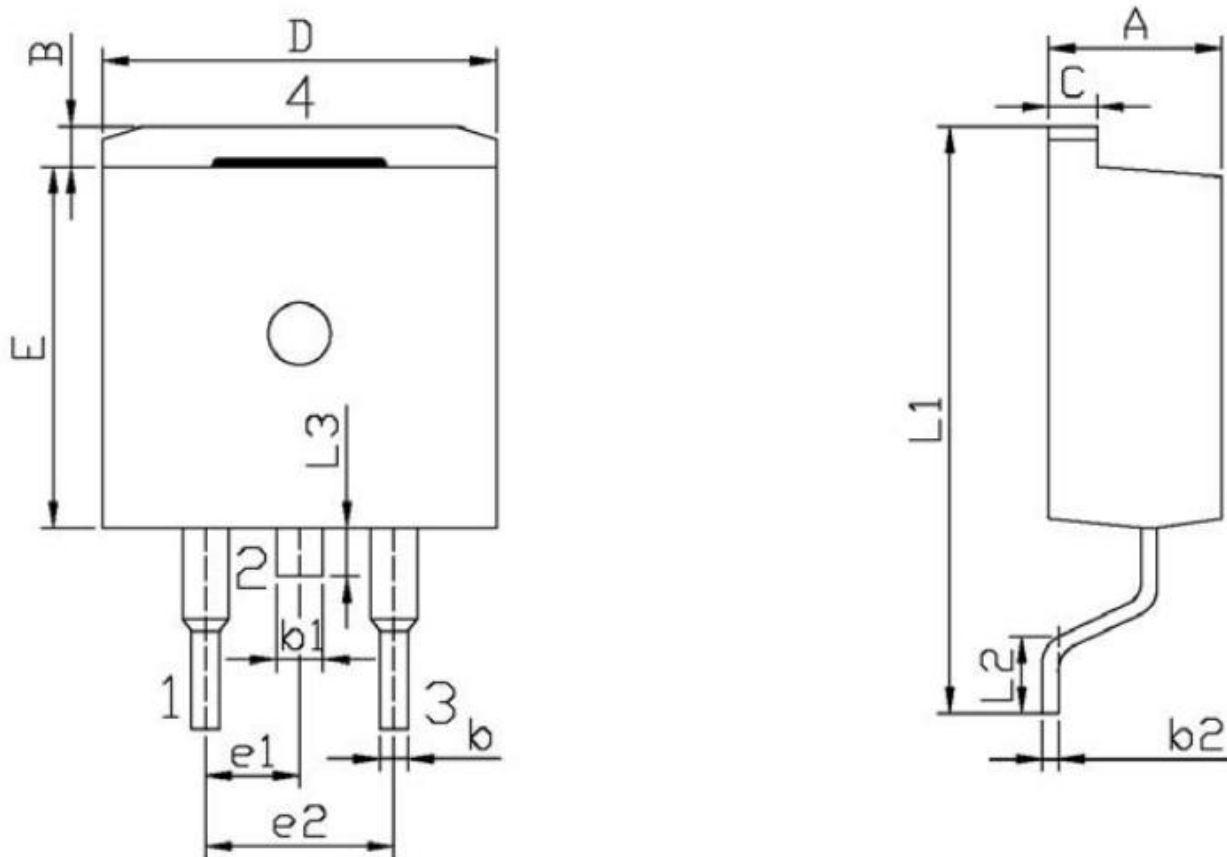


Figure 10: Source-Drain Diode Forward

**Mechanical Data:**


单位: mm

Symbol	Dimensions In Millimeters		Symbol	Dimensions In Millimeters	
	Min	Max		Min	Max
A	4.30	4.70	E	9.00	9.40
B	1.00	1.40	e1	2.34	2.74
b	0.70	0.90	e2	4.88	5.28
b1	1.15	1.35	L1	15.00	16.00
b2	0.40	0.60	L2	2.24	2.84
C	1.20	1.40	L3	1.20	1.60
D	9.80	10.20			

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Sales@silikron.com

**Technical Support:**

Technical@silikron.com

**Suzhou Silikron Semiconductor Corp.**

501 , NW-20,Nanopolis, 99th Jinjihu Avenue ,Industrial Park ,Suzhou ,P.R, CHINA

**TEL:** (86-512) 62560688

**FAX:** (86-512) 62560688-8092

**E-mail:** Sales@silikron.com